

ESD TEST REPORT

Field-Induced Charged-Device Model

JS-002-2018

ANSI/ESDA/JEDEC Standard, Method JS-002-2018 is an ESD test using Field-Induced Charged-Device Model, three positive and three negative pulses applied to the devices per customer's specification with 0.5 second cool down between pulses.

Customer : **Alpha & Omega Semiconductor (Shanghai), Ltd.**

Address: Building 8 & 9, No. 91, Lane 109, Rong Kang Road,
Songjiang Export Processing Zone, Zone B, # 888 Song Zheng Highroad, Shanghai

Device Information

Part No. :	AO4264C	Sample Size :	3pcs
Package Type :	SO8	Pin Count :	8
Lot No. :	NL005	Date Code :	-
VDD Domains :	D	VSS Domains :	S

Test Equipment

Tester1 :	ZAPMASTER MK.2 SE	Serial No. :	0508317
Calibration Date :	Jan 14 th 2021	Expiration Date :	Jan 13 th 2022
Tester2 :	Orion Robotic CDM Test System	Serial No. :	0806294
Calibration Date :	Jan 15 th 2021	Expiration Date :	Jan 14 th 2022

Environmental Condition

Temperature :	23°C	Humidity :	30% RH
Submit date :	Apr 21 st 2021	Complete date :	Apr 21 st 2021

Curve Trace Criteria

Pin Combinations	Force Voltage	Limit current
D Vs. S & G	-30V ~ +30V	50μA

Curve Trace Results Within 10% range.



Stress Summary

CDM			
Sample No.	Voltage Level	Process	Spot Test Results* (Within 10µA @ 20V between G and D/S)
12#	±2kV	All Pins Done	PASS
13#		All Pins Done	PASS
14#		All Pins Done	PASS

Test Result*

Model	Pin Combinations	ESD Sensitivity Pass*: 2kV	V Class: C3
CDM	ALL PINS DONE	±2kV	JS-002-2018 Class C0a: <125V Class C0b: 125V to <250V Class C1: 250 to <500 V Class C2a: 500 to <750 V Class C2b: 750 to <1000 V Class C3: ≥1000V

*Note: Results will be updated based on customer final electrical test results.

Test Engineer: Wenping Yan	Date: Apr 21 st 2021
Approved by FA Manager: 	Date: Apr 21 st 2021 

Recommendations

EAG Shanghai certifies that above tests have been performed in accordance to the requirements stated above and per the customer purchase order and applicable documents.

EAG Shanghai recommends electrical testing as a validation of reported results. Curve Trace criteria was utilized to specify a pass or fail. Industry standards require the device to be tested functionally at post stress and should continue to meet all electrical parameters as per the data sheet.

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